

FORM PTO-1449
U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT BY APPLICANT
 (37 CFR 1.98(b))

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 2001JP502

SERIAL NO.
 10/500,422

APPLICANT: Yoshimura, et al.

FILING DATE: 6/25/04 **GROUP:** 1751

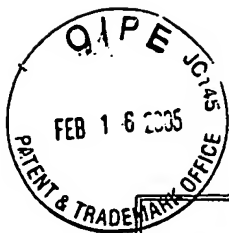
U.S. PATENT DOCUMENTS

Examiner Initial		Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
KE	AA	US 4,200,563	04/29/80	Komiya	524	817	
KE	AB	US 5,670,242	09/23/97	Asano, et al.	428	32.24	
KE	AC	US 6,165,606	12/26/00	Kasahara, et al.	428	323	
KE	AD	US 6,368,707	04/09/02	Komiya, et al.	428	349	
KE	AE	US 6,511,736	01/28/03	Asano, et al.	428	206	
KE	AF	US 6,517,941	02/11/03	Murase	428	412	

FOREIGN PATENT OR PUBLISHED FOREIGN APPLICATION

		DOCUMENT NUMBER	PUB. DATE	COUNTRY		TRANSLATION
KE	BA	JP 49-040388	4/15/74	Japan		See CA below.
	BB	JP 49-046291	12/09/74	Japan		See CB below.
	BC	JP 50-098484	08/05/75	Japan		See CC below.
	BD	JP 52-134658	11/11/77	Japan		See CD below.
	BE	JP 53-126093	11/2/78	Japan		See AA above.
	BF	JP 54-144317	11/10/79	Japan		See CE below.
	BG	JP 55-115419	09/05/80	Japan		See CF below.
	BH	JP 56-028208	03/19/81	Japan		See CG below.
	BI	JP 58-203960	11/28/83	Japan		See CH below.
	BJ	JP 62-034947	02/14/87	Japan		See CI below.
	BK	JP 62-104802	05/15/87	Japan		See CJ below.
	BL	JP 62-278081	12/02/87	Japan		See CK below.
	BM	EP 0 464 454	01/08/92	Europe		English
	BN	JP 04-050204	02/19/92	Japan		See BP below.
	BO	JP 04-053802	02/21/92	Japan		See BM above.
	BP	EP 0 472 837	03/04/92	Europe		English
	BQ	JP 05-221113	08/31/93	Japan		See CL below.
KE	BR	JP 07-149038	06/13/95	Japan		See CM below.
EXAMINER		/Kelechi Egwim/		DATE CONSIDERED		01/22/2007

EXAMINER: Initial citation considered. Draw line through citation if not in conformance with MPPE §609 and not considered. Include copy of this form with next communication to applicant.

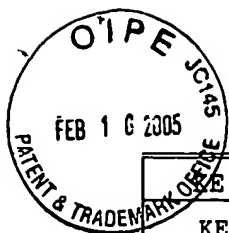


FOREIGN PATENT OR PUBLISHED FOREIGN APPLICATION (cont.)

		DOCUMENT NUMBER	PUB. DATE	COUNTRY		TRANSLATION
KE	BS	JP 09-169806	06/30/97	Japan		See CN below.
	BT	JP 10-046117	02/17/98	Japan		See AD above.
	BU	JP 10-195276	07/28/98	Japan		See CO below.
	BV	JP 10-217601	08/18/98	Japan		See CP below.
	BW	JP 10-237142	09/08/98	Japan		See CQ below.
	BX	JP 2000-118125	04/25/00	Japan		See CQ below.
	BY	WO 00/23533	04/27/00	WIPO		See AF above.
	BZ	JP 2000-211248	08/02/00	Japan		See CS below.
	B1	JP 2000-238419	09/05/00	Japan		See CT below.
	B2	EP 1 048 479	11/02/00	Europe		English
	B3	JP 2000-313847	11/14/00	Japan		See CU below.
	B4	JP 2000-318306	11/21/00	Japan		See CV below.
	B5	JP 2000-318309	11/21/00	Japan		See CW below.
	B6	EP 1 114 734	07/11/01	Europe		English
KE	B7	JP 2003-003037	01/08/03	Japan		See CX below.

OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication)

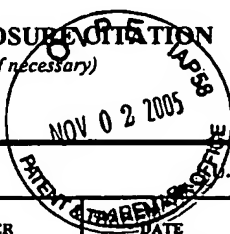
KE	CA	English abstract for publication no. JP 49-040388, 4/15/1974
	CB	English abstract for publication no. JP 49-046291, 12/09/1974
	CC	English abstract for publication no. JP 50-098484, 08/05/1975
	CD	English abstract for publication no. JP 52-134658, 11/11/1977
	CE	English abstract for publication no. JP 54-144317, 11/10/1979
	CF	English abstract for publication no. JP 55-115419, 09/05/1980
	CG	English abstract for publication no. JP 56-028208, 03/19/1981
	CH	English abstract for publication no. JP 58-203960, 11/28/1983
	CI	English abstract for publication no. JP 62-034947, 02/14/1987
	CJ	English abstract for publication no. JP 62-104802, 05/15/1987
	CK	English abstract for publication no. JP 62-278081, 12/2/1987
	CL	English abstract for publication no. JP 05-221113, 8/31/1993
	CM	English abstract for publication no. JP 07-149038, 6/13/1995
	CN	English abstract for publication no. JP 09-169806, 06/30/1997
	CO	English abstract for publication no. JP 10-195276, 7/28/1998
	CP	English abstract for publication no. JP 10-217601, 8/18/1998
	CQ	English abstract for publication no. JP 10-237142, 09/08/1998
KE	CR	English abstract for publication no. JP 2000-118125, 4/25/2000
EXAMINER /Kelechi Egwim/		DATE CONSIDERED 01/22/2007
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OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication)

KE	CS	English abstract for publication no. JP 2000-211248, 8/2/2000
KE	CT	English abstract for publication no. JP 2000-238419, 09/05/2000
KE	CU	English abstract for publication no. JP 2000-313847, 11/14/2000
KE	CV	English abstract for publication no. JP 2000-318306, 11/21/2000
KE	CW	English abstract for publication no. JP 2000-318309, 11/21/2000
KE	CX	English abstract for publication no. JP 2003-003037, 01/08/2003
	CY	
	CZ	
	C1	
	C2	
	C3	
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INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)



Docket Number (Optional) 2001JP502 (EM-05-19)		Application Number 10/500,422	
Applicant(s) N. Yoshimura et al.			
Filing Date June 25, 2004		Group Art Unit 1713	

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
KE		U.S. Patent 5,081,166	1/14/92	Kiehlbauch et al.	523	201	

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
KE		EPO Pub. 0 555 959 A1	8/18/93	EPO	C08F	265/06	✓	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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